

Notice of References CitedApplication/Control No.
09/977,994Applicant(s)/Patent Under
Reexamination
NAGATA ET ALExaminer
Jeffrey R. WestArt Unit
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Nagata et al., "Measurements and Analyses of Substrate Noise Waveform in Mixed Signal IC Environment". Proceedings of the IEEE 1999 Custom Integrated Circuits Conference. May 1999.
*	V	Shimazaki et al., "LEMMINGS: LSI's EMI-Noise Analysis With Gate Level Simulator". Proceedings of the IEEE 2000 First International Symposium on Quality Electronic Design. March 2000.
*	W	Mitra et al., "Substrate-Aware Mixed-Signal Macrocell Placement in WRIGHT". IEEE Journal of Solid-State Circuits. Vol. 30. No. 3, March 1995.
	X	Nagata et al., "Measurements and Analyses of Substrate Noise Waveform in Mixed-Signal IC Environment." IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems. Vol. 19, No. 6. June 2000.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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